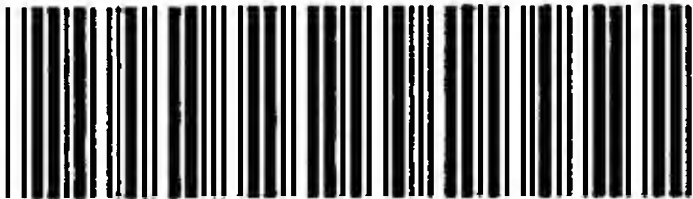


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,017	CHIOU, ING-JER	
	Examiner	Art Unit	
	Biju Chandran	2835	

SEARCHED			
Class	Subclass	Date	Examiner
361	695	1/20/2006	BIC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
see search history		